JCC6 Rec'd PCT/PTO 2.4 M PIS920020105 INFORMATION DISCLOSURE TATION (Use several shows if necessary) Doris, et al Group Art light 2826 11/25/02 To be assigned **U.S. PATENT DOCUMENTS** EXAMINER REP DUCUMENT NUMBER DATE. PILING DATE NAME CLASS SUBCLASS INDIAL IF APPROPRIATE BTL 3,602,841 8-31-71 McGroddy 4,665,415 5-12-87 Esaki, et al. 4,853,076 8-1-89 Tsaur, et al. 4,855,245 8-8-89 Neppl, et al. 4,952,524 8-28-90 Lee, et al. U.S. PATENT APPLICATION PUBLICATIONS EXAMINER FBLING DATE REP DOCUMENT NUMBER DATE INTTIAL. NAME CLASS SUBCLASS IF APPROPRIATE BTL US 2001/0009784 A1 7-26-01 Ma, et al. US 2002/0063292 A1 5-30-02 Armstrong, et al. US 2002/0074598 A1 6-20-02 Doyle, et al. US 2002/0086472 7-4-02 Roberds, et al. FOREIGN PATENT DOCUMENTS REF DOCUMENT NUMBER Translation DATE SUBCLASS COUNTRY CLASS YES NO BTL JP64-76755 03-1989 Japan OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) Kern Rim, et al., "Transconductance Enhancement in Deep Submicron Strained-Si n-MOSFETs". International Electron Devices Meeting, 26, 8, 1, IEEE, September 1998. BTL Kern Rim, et al., "Characteristics and Device Design of Sub-100 nm Strained SI N- and PMOSPET's." 2002 Symposium on VLSI Technology Digest of Technical Papers, IEEE, pp. 98-99. BTL DATE CONSIDERED / (09/13/2006) /Benjamin Tzu-Hung Liu EXAMINER EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1995 Pariu 201/PTO 2.4 MAY 20 FIS920020105 INFORMATION DISCLOSUR TATION Applicant(s) (Use several sheets if necessary) Doris, et al. Filing Date Group Art Light 2826 To be assigned 11/25/02 U.S. PATENT DOCUMENTS FRUNG DATE REF DOCUMENT NUMBER DATE NAME CLASS SUBCLASS INTITAL IP APPROPRIATE BTL 4,958,213 9-18-90 Eklund, et al. BTL 5,006,913 4-9-91 Sugabara, et al. 5,060,030 10-22-91 Hoke, et al. BTL 5,081,513 1-14-92 BTL Jackson, et al. 5,108,843 4-28-92 BTL Obtaka, et al. U.S. PATENT APPLICATION PUBLICATIONS EXAMINER REP DOCUMENT NUMBER PILING DATE DATE NAME SUBCLASS CLASS INITIAL. IF APPROPRIATE BTL US 2002/0086497 A1 7-4-02 Kwok US 2002/0090791 A1 7-11-02 Doyle, et al. BTL US 2003/0032261 A1 2-13-03 Yeb, et al. BTL US 2003/0040158 A1 2-27-03 Saitoh BTL **FOREIGN PATENT DOCUMENTS** REP DOCUMENT NUMBER DATE COUNTRY Translation CLASS. SUBCLASS NO OTHER DOCUMENTS (Including Author, Tide, Date, Pertinent Pages, Etc.) Gregory Scott, et al., "NMOS Drive Current Reduction Caused by Transistor Layout and Trench Isolation Induced Stress." International Electron Devices Meeting, 34.4.1, IEEE, September 1999. BTL F. Ootsuka, et al., "A Highly Dense, High-Performance 130mm Node CMOS Technology for Large Scale System-on-a-Chip Application." International Electron Devices Meeting, 23.5.1, IEEE, April 2000. BTL . EXAMINER /Benjamin Tzu-Hung Liu DATE CONSIDERED / (09/13/2006) EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-A820 (also form PTO-1449) 1 1

Docter Number (Optional) FIS920020105 INFORMATION DISCLOSURE TATION (Use several sheets if necessary) Doris, et al Filing Date Gmap Art lialt 2826 11/25/02 To be assigned U.S. PATENT DOCUMENTS EXAMINER FILING DATE DOCUMENT NUMBER DATE. CI.ASS SUBCLASS REP NAME DITIAL. IF APPROPRIATE 5,134,085 7-28-92 Gilgen, et al. BTL 5,310,446 5-10-94 Konishi, et al. BTL 5,354,695 10-11-94 Leedy BTL 5,371,399 12-6-94 Burroughes, et al. BTL 5,391,510 2-21-95 Hsu, et al. BTL U.S. PATENT APPLICATION PUBLICATIONS *EXAMINER FILING DATE SUBCLASS DOCUMENT NUMBER DATE NAME CLASS REP DITTAL F APPROPRIATE US 2003/0057184 A1 3-27-03 Yu, et al. BTL US 2003/0067035 A1 4-10-03 Tews, et al. BTL **FOREIGN PATENT DOCUMENTS** SUBCLASS Translation CLASS REP DOCUMENT NUMBER DATE COUNTRY YES NO (Including Author, Title, Date, Pertinent Pages, Etc.) OTHER DOCUMENTS Shinya Ito, et al., "Mechanical Stress Effect of Etch-Stop Nitride and its Impact on Deep Submicron Transistor Design." International Electron Devices Meeting, 10.7.1, IEEE, April 2000. BTL A. Shimizu, et al., "Local Mechanical-Stress Control (LMC): A New Technique for CMOS-Performance Enhancement." International Electron Devices Meeting, IEEE, March 2001. BTL

EXAMINER: Initial if cliation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

EXAMINER

/Benjamin Tzu-Hung Liu

DATE CONSIDERED / (09/13/2006)

JCGS Rec'd PCT/PTO 24 MAY 2005

INFORMATION DISCLOSUR TATION					PIS920020105 Applicant(s) Ducker Nouther (Optings) Applicant(s)					
		(Use several sheets if necess.	aris)		Doris, et al. Filing Date		Group Art tids 2		2826	
11/25/02 To be assign						ned				
	,	Y	U.	S. PATENT	DOCUMENTS	· 	1			
'EXAMINER INTTIAL	R.F.P	DUCUMENT NUMBER	DATE		NAME		SUBCLASS		G DATE ROPRIATE	
BTL		5,459,346	10-17-95	Asakaw	va, et al.					
BTL		5,471,948	12-5-95	Burrou	ghes, et al.					
BTL		5,557,122	9-17-96	Shrivas	tava, et al.	_ \				
BTL		5,561,302	10-1-96	Candela	aria					
BTL		5,565,697	10-15-96	Asakaw	a, et al.					
			U.S. PATEN	T APPLICA	TION PUBLICATIONS		"			
*EXAMINER DITTIAL	OFF BOCKWENT NUMBER		DATE		NAME CLASS SUBCLA		SUBCLASS	FTLING DATE JP APPROPRIATE		
							· _			
						·				
·										
_			FORE	IGN PATE	NT DOCUMENTS		_			
	REF	REF DOCUMENT NUMBER DATE			COUNTRY		SUBCLASS	Translation YES NO		
					•					
				OCUMENT						
BTL		K. Ota, et al., "Novel Lo Devices Meeting, 2.2.1, 1	cally Strained Cl IEEE, Pebruary	hannel Tec 2002.	hnique for High Perform	isace 55am CM	OS." Internat	ional Elec	rtros	
BTL		G. Zhang, et al., "A New 'Mixed-Mode' Reliability Degradation Mechanism in Advanced Si and SiGe Bipolar Transistors." IEEE Transactions on Electron Devices, vol. 49, no. 12, December 2002, pp. 2151-56.								
EXAMINER /B	XAMINER /Benjamin Tzu-Hung Liu				DATE CONSIDERED / (09/13/2006)					
EXAMINER	t: Inkla	lif citation considered, whether o			e with MPEP Section 609; D	raw Lae through	citation if not in	conforman	nce and	

PIS920020105 INFORMATION DISCLOSUR TATION (Use several sheets if necessary) Doris, et al Filing Date Group Art Unit 2826 11/25/02 To be assigned **ILS. PATENT DOCUMENTS** EXAMINER FULING DATE REP DUCUMENT NUMBER NAME. FUBCLASS CLASS INITIAL. IF APPROPRIATE 5,571,741 11-5-96 Leedy BTL 5,592,007 1-7-97 Leedy BTL 5,592,018 1-7-97 Leedy BTL 5,670,798 9-23-97 Schetzina BTL 5,679,965 BTL 10-21-97 Schetzina U.S. PATENT APPLICATION PUBLICATIONS EXAMPLE PILING DATE DOCUMENT NUMBER REP DATE INTTAL NAME CLASS **5UBCLASS** IF APPROPRIATE FOREIGN PATENT DOCUMENTS RIG DOCUMENT NUMBER Translation DATE COUNTRY **SUBCLASS** CLASS YES NO OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) H.S. Momose, et al., "Temperature Dependence of Emitter-Base Reverse Stress Degradation and its Mechanism Analyzed by MOS Structures." Paper 6.2, pp. 140-143. BTL C.J. Huang, et al., "Temperature Dependence and Post-Stress Recovery of Hot Electron Degradation Effects in Bipolar Transistors." IEEE 1991 Bipolar Circuits and Technology Meeting 7.5, pp. 170-173. BTL

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

/Benjamin Tzu-Hung Liu

EXAMINER

DATE CONSIDERED

/ (09/13/2006)

ICOG ROC'C PUTPTO X4 MAY 2005 F1S920020105 Applicant(s) Doris, et al. Filling Date Group Art l'ait 2826 11/25/02 To be assigned U.S. PATENT DOCUMENTS PULING DATE NAME CLASS SUBCLASS IF APPROPRIATE Candelaria Leedy Brasen, et al. Sun, et al. Jin, et al. · U.S. PATENT APPLICATION PUBLICATIONS FILING DATE NAME 8UBCLASS CLASS EF APPROPRIATE **FOREIGN PATENT DOCUMENTS** COUNTRY SUBCLASS NO YES

INFORMATION DISCLOSUR TATION

DATE

11-4-97

11-24-98

1-19-99

3-9-99

8-17-99

DATE

(Use several sheets if necessary)

DOCUMENT NUMBER

DOCUMENT NUMBER

DOCUMENT NUMBER

5,683,934

5,840,593

5,861,651

5,880,040

5,940,716

	OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	
BTL	S.R. Sbeng, et al., "Degradation and Recovery of SiGe HBTs Following Radiation and Hot-Carrier Stressing." Pp. 14-15.	
BTL	Z. Yang, et al., "Avalanche Current Induced Hot Carrier Degradation in 200 GHz SiGe Heterojunction Bipolar Transistors." Pp. 1-5.	_

EXAMINER

*FXAMINER

INTIAL.

BTL

BTL BTL

BTL

BTL

NE MENTENER

INITIAL.

REP

REP

/Benjamin Tzu-Hung Liu

DATE CONSIDERED

/ (09/13/2006)

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and oot considered. Include copy of this form with next communication to applicant.

JC06 Rec'd PCT/PTO 24 F1S920020105 Applicant(s) Doris, et al. Filing Date Grosp Art Links 2826 11/25/02 To be assigned PILING DATE NAME CLASS FURCI.ASS IF APPROPRIATE PILING DATE NAME CLASS **SUBCLASS** IF APPROPRIATE Translation CLASS SUBCLASS COUNTRY YES NO

INFORMATION DISCLOSUR TATION (Use several sheets if necessary) U.S. PATENT DOCUMENTS EXAMINEN DOCUMENT NUMBER DATE ENTITAL. BTL 5,940,736 8-17-99 Brady, et al. 5,946,559 8-31-99 Leedy BTL BTL 9-28-99 5,960,297 Saki 5,989,978 11-23-99 Peidous BTL BTL 6,008,126 12-28-99 Leedy U.S. PATENT APPLICATION PUBLICATIONS EXAMINER REP DOCUMENT NUMBER DATE DUTTAL. FOREIGN PATENT DOCUMENTS REP DOCUMENT NUMBER DATE OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) H. Ll, et al., "Design of W-Band VCOs with High Output Power for Potential Application in 77 GHz Automotive Radar Systems." 2003 IEEE GaAs Digest, pp. 263-66. BTL H. Wurzer, et al., "Annealing of Degraded non-Transistors- Mechanisms and Modeling." IEEE Transactions on Electron Devices, vol. 41, no. 4, April 1994, pp. 533-38. BTL **EXAMINER DATE CONSIDERED** / (09/13/2006) /Benjamin Tzu-Hung Liu

EXAMINER: Initial If citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

icos Bor'd PCT/PTU 24 MA PIS920020105 TATION INFORMATION DISCLOSU (Use several sheets if necessary) Doris, et al Group Art light Filing Date 2826 11/25/02 To be assigned U.S. PATENT DOCUMENTS EXAMINER FILING DATE. REP DOCUMENT NUMBER DATE CLASS SUBCLASS INSTIAL. IF APPROPRIATE 6,025,280 2-15-00 Brady, et al. 6,046,464 4-4-00 Schetzina BTL 6,066,545 5-23-00 Doshi, et al. BTL 6,090,684 7-18-00 BTL Ishitsuka, et al. 6,107,143 8-22-00 BTL Park, et al. U.S. PATENT APPLICATION PUBLICATIONS "EXAMINER PILING DATE DOCUMENT NUMBER DATE NAME CLASS SUBCLASS DITIAL IF APPROPRIATE FOREIGN PATENT DOCUMENTS Tresslatio DOCUMENT NUMBER DATE COUNTRY CLASS **SUBCLASS** YES NO OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) B. Doyle, et al., "Recovery of Hot-Carrier Damage in Reoxidized Nitrided Oxide MOSFETs." IEEE Electron Device Letters, vol. 13, no. 1, January 1992, pp. 38-40. BTL H.S. Momose, et al., "Analysis of the Temperature Dependence of Hot-Carrier-Induced Degradation in Bipolar Transistors for Bi-CMOS." IEEE Transactions on Electron Devices, vol. 41, no. 6, June 1994, pp. 978-987. BTL **EXAMINER** DATE CONSIDERED /Benjamin Tzu-Hung Liu / (09/13/2006) EXAMINER: Initial If cliation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and

Form PTO-A820 (also form PTO-1449)

not considered. Include copy of this form with next communication to applicant.

PIS920020105 INFORMATION DISCLOSUR MOLLET Applicost(s) (Use reveral sheets if necessary) Doris, et al. Filing Date Group Art tinti To be assigned 2826 11/25/02 U.S. PATENT DOCUMENTS EXAMINER FULING DATE RFF DOCUMENT NUMBER DATE NAME CLASS. SUBCLASS INTITAL. IF APPROPRIATE BTL 6,117,722 9-12-00 Wuu, et al. 6,133,071 10-17-00 BTL Nagai 6,165,383 12-26-00 Chou BTL 6,221,735 4-24-01 Manley, et al. BTL 6,228,694 5-8-01 BTL Doyle, et al. U.S. PATENT APPLICATION PUBLICATIONS EXAMINER DOCUMENT NUMBER FOLING DATE DATE NAME CLASS SUBCLASS INITIAL P'APPROPRIATE FOREIGN PATENT DOCUMENTS DOCUMENT NUMBER DATE CLASS Translation COUNTRY **SUBCLASS OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and

Form PTO-A820 (also form PTO-1449)

not considered. Include copy of this form with next communication to applicant.

FIS920020105 INFORMATION DISCLOSUR TATION Applicant(s) (Use several sheets if necessary) Doris, et al. Filing Date Gmap Art l'ait 11/25/02 To be assigned U.S. PATENT DOCUMENTS EXAMINER FULING DATE DOCUMENT NUMBER DATE NAME CLASS SUBITLASS INTITAL. IF APPROPRIATE BTL 6,246,095 6-12-01 Brady, et al. 6,255,169 7-3-01 Li, et al. BTL 6,261,964 7-17-01 Wo, et al. BTL 6,265,317 7-24-01 Chiu, et al. BTL 6,274,444 8-14-01 Wang BTL U.S. PATENT APPLICATION PUBLICATIONS 'EXAMINER DOCUMENT NUMBER DATE PILING DATE CLASS NAME SUBCLASS INITIAL IF APPROPRIATE FOREIGN PATENT DOCUMENTS DOCUMENT NUMBER DATE COUNTRY CLASS **SUBCLASS** Trembilee YES NO OTHER DOCUMENTS (Including Author, Tide, Date, Pertinent Pages, Etc.) EXAMINER DATE CONSIDERED / (09/13/2006) . /Benjamin Tzu-Hung Liu EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Docket Number (Optional) P15920020105 INFORMATION DISCLOSUR TATION Applicant(s) (Use several sheets if necessary) Doris, et al Filling Date Group Art Link 2826 11/25/02 To be assigned U.S. PATENT DOCUMENTS EXAMINER FILING DATE REF DUCUMENT NUMBER DATE NAME CLASS SUBCLASS INITIAL, IF APPROPRIATE 6,281,532 8-28-01 BTL Doyle, et al. 6,284,623 9-4-01 Zhang, et al. BTL 6,284,626 9-4-01 Kim BTL BTL 6,319,794 11-20-01 Akatsu, et al. 6,361,885 3-26-02 BTL Chon U.S. PATENT APPLICATION PUBLICATIONS *EXAMINER REP DOCUMENT NUMBER DATE FILING DATE NAME CLASS SUBCLASS INTTAL. IF APPROPRIATE FOREIGN PATENT DOCUMENTS Transi RKP DOCUMENT NUMBER DATE COUNTRY CLA58 SUBCLASS YES NO OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

PYANDER 1-44

EXAMINER

/Benjamin Tzu-Hung Liu

DATE CONSIDERED

/ (09/13/2006)

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1005 PSC'A PCT/PTO 24 MAY 2009

INFORMATION DISCLOSUR TATION					PIS920020105 Applicant(s)		THE LESTING 483			
		(Use several sheets if news	(יְרָשׁצּ)		Doris, et al.	·				
			• •	Filing Date 11/25/02	Group Art l'ali To be assi	Group Art Unit				
	***	······································	U.	S. PATENT	DOCUMENTS		to be assi	gned		
*EXAMINEN INITIAL	REF	DOCUMENT NUMBER			SUBCLASS -		C DATE			
BTL		6,362,082	3-26-02	Doyle, e	t al.			IF APPROPRIATY		
BTL	, i.	6,368,931	4-9-02	Kubn, e	t al.	1.		1		
BTL		6,403,486	6-11-02	Lou		į				
BTL		6,403,975	6-11-02	Brunner	r, et al.					
BTL		6,406,973	6-18-02	Lee	Lee					
			U.S. PATEN	T APPLICA	TION PUBLICATIONS					
*EXAMINER INITIAL			DATE		NAME	CLASS	SUBCLASS	PILING DATE IF APPROPRIATE.		
						,				
			FORE	ign paten	T DOCUMENTS					
	REF	SF DOCUMENT NUMBER DATE			COUNTRY	CLASS	8UBCLASS	Tres	station NO	
					*					
					,					
			OTHER D	OCUMENT	S (Including Author,	Title, Date, Per	rtinent Pages, Etc	,		
			·							
EXAMINER		/Benjamin Tzu-Hung	Liu	1	DATE CONSIDERED	/ (09/13/2	006)			
EXAMINER 101 considere	: loitia d. lod	if citation considered, whether oude copy of this form with next c	or not citation is in communication to ap	conformance opticant.	with MPEP Section 609; Dra	w line through	distinct if not in	conforma	ice and	

ICCG Bec'd PCT/PTO 2 A PIS920020105 INFORMATION DISCLOSUR TATION Applicant(s) (Use sewral shorts if necessary) Doris, et al Group Art Linis 11/25/02 To be assigned **U.S. PATENT DOCUMENTS** EXAMINER FULING DATE REP DOCUMENT NUMBER DATE. NAME CLASS SUBCLASS INITIAL. IF APPROPRIATE BTL 6,461,936 10-8-02 von Ebrenwall 6,476,462 11-5-02 Shimizu, et al. BTL 6,483,171 11-19-02 Forbes, et al. BTL 6,493,497 12-10-02 Ramdani, et al. BTL 6,498,358 12-24-02 Lach, et al. BTL U.S. PATENT APPLICATION PUBLICATIONS *EXAMINER filing date DOCUMENT NUMBER DATE NAME. CI.ASS SUBCI.ASS INTTEAL IP APPROPRIATE FOREIGN PATENT DOCUMENTS REF DOCUMENT NUMBER DATE COUNTRY CLAS5 **SUBCLASS** YES NO **OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.) **EXAMINER DATE CONSIDERED** / (09/13/2006) /Benjamin Tzu-Hung Liu EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ICCO Rec'd PCT/PTO 2.4 MAY 2005

INFORMATION DISCLOSUS TATION				PIS920020105 Applicant(s)	TO 15 5 36 483					
		(Use several sheets if news			Doris, et al.					
					Filing Date 11/25/02	.	Group Art (id)			
			U	S. PATENT	DOCUMENTS		To be assig	ned	<u> </u>	
*EXAMINER	RF.F	DOCUMENT NUMBER			NAME	CLASS	SUBCLASS	PRING DATE		
BTL		6,501,121	12-31-02	Yu, ct al.				IF APPR	OPRIATE:	
BTL		6,506,652	1-14-03	Jan, et al.						
BTL		6,509,618	1-21-03	Jan, et	al. ·					
BTL		6,521,964	2-18-03	Jan, et	Jan, et al.			·		
RTI		6,531,369	3-11-03	Ozkan,	et aL	·				
			U.S. PATEN	T APPLICA	TION PUBLICATIONS		.			
'EXAMINER INITIAL				NAME CLASS		SUBCLASS	FILING DATE IF APPROPRIATE			
					·					
		·								
					•			: 		
			<u> </u>	<u> </u>	····					
			FORE	EIGN PATE!	NT DOCUMENTS				<u>:</u>	
	REP DOCUMENT NUMBER DATE			COUNTRY		SUBCLASS	YES .	NO .		
		·								
			OTHER I	DOCUMENT	(Including Author	r, Tide, Date, Per	tinent Pages, Etc.	<u>, </u>		
			·			<u>.</u>			·	
						, .				
				<u>-</u>	NAME AND THE PROPERTY OF		/200C)			
EXAMINER	` ——	/Benjamin Tzu-R	ung Liu		DATE CONSIDERED	/ (09/13	5/2006}			
		l if citation considered, whether hade copy of this form with next			e with MPEP Section 609; D	raw line through	citation if not in	conjórman	ban so	

JC06 Rec'd PCT/PTO 2.4 MAY 2005 Docket Number (Optional) FIS920020105 INFORMATION DISCLOSU TATION Applicunt(s) (Use several sheets if necessary) Doris, et al Group Art Linds Filing Date 2826 11/25/02 To be assigned U.S. PATENT DOCUMENTS EXAMINER FILING DATE REF DOCUMENT NUMBER DATE NAME CLASS SUDCLASS INITIAL IF APPROPRIATE 6,531,740 3-11-03 Bosco, et al. BTL 6,621,392 9-16-03 Volant, et al. BTL 6,635,506 10-21-03 Volant, et al. BTL U.S. PATENT APPLICATION PUBLICATIONS EXAMINER FILING DATE DOCUMENT NUMBER DATE CLASS SUBCLASS REF NAME. INITIAL IF APPROPRIATE FOREIGN PATENT DOCUMENTS DOCUMENT NUMBER DATE COUNTRY CLAS8 SUBCLASS YES NO OTHER DOCUMENTS (Including Author, Tide, Date, Pertinent Pages, Etc.) **EXAMINER** DATE CONSIDERED / (09/13/2006) /Benjamin Tzu-Hung Liu EXAMINER: Initial if cliation considered, whether or not cliation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FIS9200201 INFORMATION DISCLOSE CITATION Applicant(s) (Use several sheets if necessary) Doris, et al. Filing Date Group Art Unit 2826 11/25/02 To be assigned U.S. PATENT DOCUMENTS EXAMINER 227 DOCUMENT NUMBER FILING DATE DATE NAME SUBCLASS CLASS DOTTAL TY APPROPRIATE 6,342,410 1-29-02 BTL Yu 6,413,802 7-2-02 Hu, et al. BTL 6,433,609 8-13-02 Voldman BTL BTL 6,458,662 10-1-02 Yu U.S. PATENT APPLICATION PUBLICATIONS *EXAMINER REF FILING DATE DOCUMENT NUMBER DATE NAME CLASS SUBCLASS DITTIAL IF APPROPRIATE FOREIGN PATENT DOCUMENTS REF DOCUMENT NUMBER DATE COUNTRY CLASS SUBCLASS YES NO OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Form PTO-A820 (also form PTO-1449)

/Benjamin Tzu-Hung Liu

not considered. Include copy of this form with next communication to applicant.

EXAMINER

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and

DATE CONSIDERED

/ (09/13/2006)